

November 2009

# ISL9V5036S3S / ISL9V5036P3 / ISL9V5036S3

## EcoSPARK® 500mJ, 360V, N-Channel Ignition IGBT

### **General Description**

The ISL9V5036S3S, ISL9V5036P3, and ISL9V5036S3 are the next generation IGBTs that offer outstanding SCIS capability in the D²-Pak (TO-263) and TO-220 plastic package. These devices are intended for use in automotive ignition circuits, specifically as coil drivers. Internal diodes provide voltage clamping without the need for external components.

**EcoSPARK®** devices can be custom made to specific clamp voltages. Contact your nearest Fairchild sales office for more information.

Formerly Developmental Type 49443

### **Applications**

- Automotive Ignition Coil Driver Circuits
- · Coil-On Plug Applications

#### **Features**

- Industry Standard D<sup>2</sup>-Pak package
- SCIS Energy = 500mJ at T<sub>J</sub> = 25°C
- · Logic Level Gate Drive
- Qualified to AEC Q101
- RoHS Compliant



# Package Symbol JEDEC TO-263AB JEDEC TO-220AB JEDEC TO-262AA BC GATE COLLECTOR (FLANGE) COLLECTOR (FLANGE)

# **Device Maximum Ratings** T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage (I <sub>C</sub> = 1 mA)	390	V	
BV <sub>ECS</sub>	Emitter to Collector Voltage - Reverse Battery Condition (I <sub>C</sub> = 10 mA) 24			
E <sub>SCIS25</sub>	At Starting $T_J = 25^{\circ}\text{C}$ , $I_{SCIS} = 38.5\text{A}$ , $L = 670 \mu\text{Hy}$ 500			
E <sub>SCIS150</sub>	At Starting $T_J = 150$ °C, $I_{SCIS} = 30$ A, $L = 670 \mu$ Hy	300	mJ	
I <sub>C25</sub>	Collector Current Continuous, At T <sub>C</sub> = 25°C, See Fig 9	46	Α	
I <sub>C110</sub>	Collector Current Continuous, At T <sub>C</sub> = 110°C, See Fig 9	31	Α	
$V_{GEM}$	Gate to Emitter Voltage Continuous	±10	V	
P <sub>D</sub>	Power Dissipation Total T <sub>C</sub> = 25°C	250	W	
	Power Dissipation Derating T <sub>C</sub> > 25°C	1.67	W/°C	
TJ	Operating Junction Temperature Range	-40 to 175	°C	
T <sub>STG</sub>	Storage Junction Temperature Range	-40 to 175	°C	
T <sub>L</sub>	Max Lead Temp for Soldering (Leads at 1.6mm from Case for 10s)	300	°C	
T <sub>pkg</sub>	Max Lead Temp for Soldering (Package Body for 10s)	260	°C	
ESD	Electrostatic Discharge Voltage at 100pF, 1500Ω	4	kV	

Symbol

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
V5036S	ISL9V5036S3ST	TO-263AB	330mm	24mm	800
V5036P	ISL9V5036P3	TO-220AA	Tube	N/A	50
V5036S	ISL9V5036S3	TO-262AA	Tube	N/A	50
V5036S	ISL9V5036S3S	TO-263AB	Tube	N/A	50

**Test Conditions** 

Min

Тур

Max Units

# **Electrical Characteristics** $T_A = 25$ °C unless otherwise noted

Parameter

D\/	Collector to Emitter Prockdown Voltage	1 - 2m / \/	0	330	360	390	- 1/
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage	$I_C = 2\text{mA}, V_{GE} = 0,$ $R_G = 1\text{K}\Omega$ , See Fig. 15 $T_J = -40 \text{ to } 150^{\circ}\text{C}$		330	300	390	\ 
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	$I_C = 10$ mA, $V_{GE} = 0$ , $R_G = 0$ , See Fig. 15 $T_J = -40$ to 150°C		360	390	420	V
BV <sub>ECS</sub>	Emitter to Collector Breakdown Voltage	$I_C = -75 \text{mA}, V_{GE} = 0 \text{V},$ $T_C = 25 ^{\circ}\text{C}$		30	-	-	V
BV <sub>GES</sub>	Gate to Emitter Breakdown Voltage	I <sub>GES</sub> = ± 2mA		±12	±14	-	V
I <sub>CER</sub>	Collector to Emitter Leakage Current	$V_{CER} = 250V$ ,	$T_C = 25^{\circ}C$	-	-	25	μA
		$R_G = 1K\Omega$ , See Fig. 11	T <sub>C</sub> = 150°C	-	-	1	m/
I <sub>ECS</sub>	Emitter to Collector Leakage Current	$V_{EC} = 24V$ , See	$T_C = 25^{\circ}C$	-	-	1	m/
		Fig. 11	$T_{\rm C} = 150^{\circ}{\rm C}$	-	-	40	m/
R <sub>1</sub>	Series Gate Resistance			-	75	-	Ω
R <sub>2</sub>	Gate to Emitter Resistance			10K	-	30K	Ω

## **On State Characteristics**

V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage		T <sub>C</sub> = 25°C, See Fig. 4	-	1.17	1.60	V
V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	$I_C = 15A,$ $V_{GF} = 4.5V$	T <sub>C</sub> = 150°C	-	1.50	1.80	V

## **Dynamic Characteristics**

Q <sub>G(ON)</sub>	Gate Charge	$I_C = 10A, V_{CE} = V_{GE} = 5V, See$		-	32	-	nC
V <sub>GE(TH)</sub>	Gate to Emitter Threshold Voltage	$I_C = 1.0 \text{mA},$	$T_C = 25$ °C	1.3	-	2.2	V
		V <sub>CE</sub> = V <sub>GE,</sub> See Fig. 10	T <sub>C</sub> = 150°C	0.75	ı	1.8	V
V <sub>GEP</sub>	Gate to Emitter Plateau Voltage	$I_{\rm C} = 10A$ ,	V <sub>CE</sub> = 12V	-	3.0	-	V

## **Switching Characteristics**

t <sub>d(ON)R</sub>	Current Turn-On Delay Time-Resistive	$V_{CE} = 14V, R_{L} = 1\Omega,$	-	0.7	4	μs
t <sub>rR</sub>	Current Rise Time-Resistive	$V_{GE}$ = 5V, $R_G$ = 1K $\Omega$ $T_J$ = 25°C, See Fig. 12	-	2.1	7	μs
t <sub>d(OFF)L</sub>	Current Turn-Off Delay Time-Inductive	$V_{CE} = 300V, L = 2mH,$	-	10.8	15	μs
t <sub>fL</sub>	Current Fall Time-Inductive	$V_{GE}$ = 5V, $R_G$ = 1K $\Omega$ $T_J$ = 25°C, See Fig. 12	-	2.8	15	μs
SCIS	Self Clamped Inductive Switching	$T_J$ = 25°C, L = 670 μH, $R_G$ = 1KΩ, $V_{GE}$ = 5V, See Fig. 1 & 2	-	-	500	mJ

## **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance Junction-Case	TO-263, TO-220, TO-262	-	-	0.6	°C/W

# **Typical Characteristics**

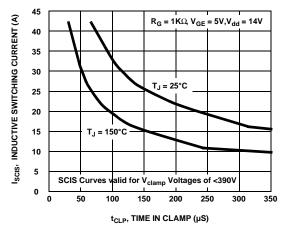
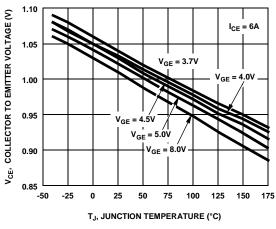


Figure 1. Self Clamped Inductive Switching Current vs Time in Clamp

Figure 2. Self Clamped Inductive Switching Current vs Inductance



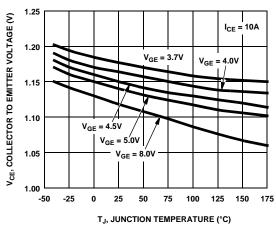
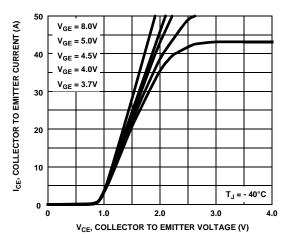


Figure 3. Collector to Emitter On-State Voltage vs Junction Temperature

Figure 4.Collector to Emitter On-State Voltage vs Junction Temperature



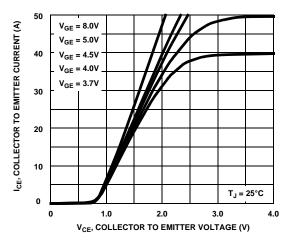
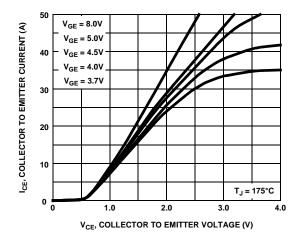


Figure 5. Collector Current vs Collector to Emitter On-State Voltage

Figure 6. Collector Current vs Collector to Emitter On-State Voltage

## Typical Characteristics (Continued)



DUTY CYCLE < 0.5%, V<sub>CE</sub> = 5V
PULSE DURATION = 250µs

T<sub>J</sub> = 175°C

T<sub>J</sub> = 25°C

T<sub>J</sub> = -40°C

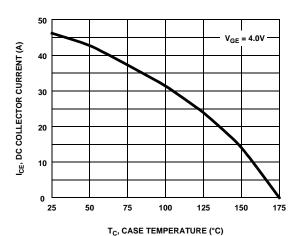
1.0

1.5

V<sub>GE</sub>, GATE TO EMITTER VOLTAGE (V)

Figure 7. Collector to Emitter On-State Voltage vs Collector Current

Figure 8. Transfer Characteristics



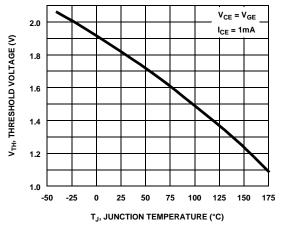
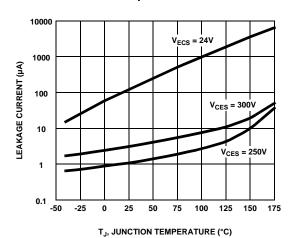


Figure 9. DC Collector Current vs Case Temperature

Figure 10. Threshold Voltage vs Junction Temperature



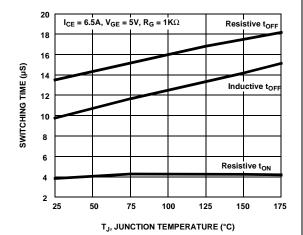
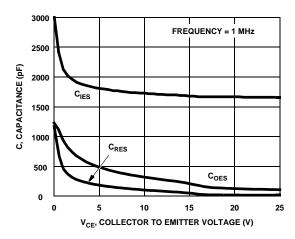


Figure 11. Leakage Current vs Junction Temperature

Figure 12. Switching Time vs Junction Temperature

# Typical Characteristics (Continued)



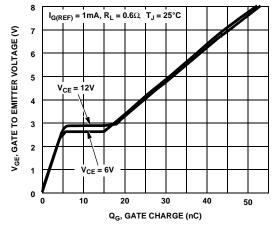


Figure 13. Capacitance vs Collector to Emitter Voltage

Figure 14. Gate Charge

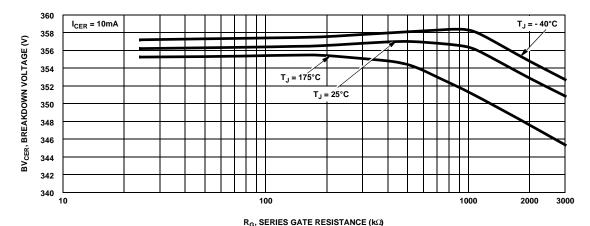


Figure 15. Breakdown Voltage vs Series Gate Resistance

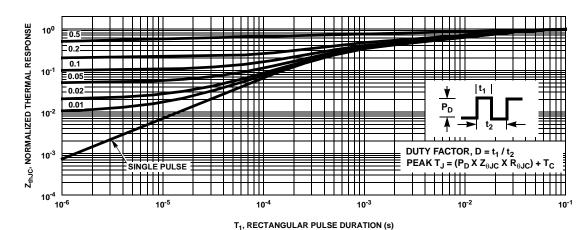
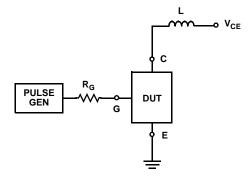


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

# **Test Circuits and Waveforms**



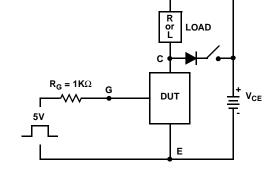


Figure 17. Inductive Switching Test Circuit

Figure 18.  $t_{ON}$  and  $t_{OFF}$  Switching Test Circuit

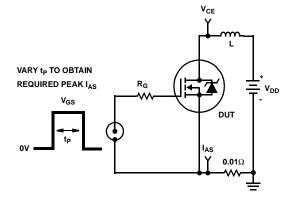


Figure 19. Energy Test Circuit

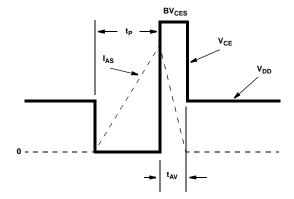


Figure 20. Energy Waveforms

#### SPICE Thermal Model JUNCTION REV 1 May 2002 ISL9V5036S3S / ISL9V3536P3 / ISL9V5036S3 CTHERM1 th 6 4.0e2 CTHERM2 6 5 3.6e-3 CTHERM3 5 4 4.9e-2 RTHERM1 CTHERM1 CTHERM4 4 3 3.2e-1 CTHERM5 3 2 3.0e-1 CTHERM6 2 tl 1.6e-2 6 RTHERM1 th 6 1.0e-2 RTHERM2 6 5 1.4e-1 RTHERM3 5 4 1.0e-1 RTHERM2 CTHERM2 RTHERM4 4 3 9.0e-2 RTHERM5 3 2 9.4e-2 RTHERM6 2 tl 1.9e-2 5 SABER Thermal Model SABER thermal model ISL9V5036S3S / ISL9V5036P3 / ISL9V5036S3 RTHERM3 CTHERM3 template thermal\_model th tl thermal\_c th, tl ctherm.ctherm1 th 6 = 4.0e2ctherm.ctherm2 65 = 3.6e-3ctherm.ctherm3 5 4 = 4.9e-2ctherm.ctherm4 43 = 3.2e-1RTHERM4 CTHERM4 ctherm.ctherm5 3 2 = 3.0e-1ctherm.ctherm6 2 tl = 1.6e-2 rtherm.rtherm1 th 6 = 1.0e-2 3 rtherm.rtherm2 6 5 = 1.4e-1rtherm.rtherm354 = 1.0e-1rtherm.rtherm4 43 = 9.0e-2RTHERM5 CTHERM5 rtherm.rtherm5 3 2 = 9.4e-2rtherm.rtherm6 2 tl = 1.9e-2 2 RTHERM6 CTHERM6 CASE

SEMICONDUCTOR

## TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidiaries, and is not intended to be an exhaustive list of all such trademarks.

AccuPower™
Auto-SPM™
Build it Now™
CorePLUS™
CorePOWER™
CROSSVOL™

CTL™
Current Transfer Logic™
EcoSPARK®
EfficientMax™
EZSWITCH™\*

Fairchild<sup>®</sup>
Fairchild Semiconductor<sup>®</sup>
FACT Quiet Series<sup>™</sup>

FACT®
FAST®
FastvCore™
FETBench™

FlashWriter®\*
FPS™
F-PFS™
FRFET®

Global Power Resource<sup>SM</sup> Green FPS™ Green FPS™ e-Series™ G*max*™

GTO<sup>TM</sup>
IntelliMAX<sup>TM</sup>
ISOPLANAR<sup>TM</sup>
MegaBuck<sup>TM</sup>
MICROCOUPLER<sup>TM</sup>
MicroFET<sup>TM</sup>
MicroPak<sup>TM</sup>
MillerDrive<sup>TM</sup>
MotionMax<sup>TM</sup>
Motion-SPMT<sup>TM</sup>
OPTOLOGIC<sup>®</sup>

PDP SPM™

OPTOPLANAR®

Power-SPM™ PowerTrench® PowerXS™

Programmable Active Droop™

QFET<sup>®</sup>
QS<sup>™</sup>
Quiet Series<sup>™</sup>
RapidConfigure<sup>™</sup>

Saving our world, 1mW/W/kW at a time™ SignalWise™

SmartMax<sup>TM</sup>
SMART START<sup>TM</sup>
SPM<sup>®</sup>
STEALTH<sup>TM</sup>

STEALTH
SuperFETTM
SuperSOTTM-3
SuperSOTTM-6
SuperSOTTM-8
SupreMOSTM
SyncFETTM
Sync-LockTM

The Power Franchise®
the Power Franchise®
TinyBoost™
TinyBuck™
TinyCalc™
TinyLogic®
TINYOPTO™
TinyPower™
TinyPwM™
TinyPwWire™
TinyPwWire™
TriFault Detect™
TRUECURRENT™\*

µSerDes™

UHC®

Ultra FRFET™

UniFET™

VCX™

VisualMax™

XS™

#### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufacturers of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed applications, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handling and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address any warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

#### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Datasheet Identification   Product Status		Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I43

<sup>\*</sup> Trademarks of System General Corporation, used under license by Fairchild Semiconductor.